

Search Notes 	Application/Control No.	Applicant(s)/Patent under Reexamination	
	09/558,472	BRISTOW ET AL.	
	Examiner	Art Unit	
	Shin-Lin Chen	1632	

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
514	44		
435	455		
536	23.5	9/6/2008	SLC